

600V Super-junction Power MOSFET

DESCRIPTION

600V Super-junction Power MOSFET

Super-junction power MOSFET is a revolutionary technology for high voltage power MOSFETs, designed according to the SJ principle and pioneered. The Multi-EPI SJ MOSFET provide an extremely fast and robust body diode. Also provide an extremely low switching, communication and conduction losses device with highest robustness make especially resonant switching applications more reliable, more efficient, lighter and cooler, designed by Wuxi Unigroup Microelectronics Company.

FEATURES APPLICATIONS Ultra-fast body diode Switch Mode Power Supply (SMPS) Very low FOM $R_{DS(on)} \times Q_g$ Uninterruptible Power Supply (UPS) Easy to use/drive Power Factor Correction (PFC) 100% avalanche tested LLC Half-bridge **RoHS** compliant Charger Drain TO-220 Gate Source

Device Marking and Package Information					
Device	Package	Marking			
TPA60R170MFD	TO-220F	60R170MFD			
Key Performance Parameters					
Parameter	Value	Unit			
V _{DS} @ T _{j,max}	600	V			
R _{DS(on),max}	0.17	Ω			
I _D	20	А			
Q _{g,typ}	41	nC			
I _{DM}	60	A			
t _{rr}	144	ns			
Q _{rr}	0.76	μC			
I _{rrm}	10.5	A			



Absolute Maximum Ratings $T_c = 25^{\circ}C$, unless otherwise noted						
Parameter		Symbol	Value	Unit		
Drain-Source Voltage (V _{GS} = 0V)		V _{DSS}	600	V		
Continuous Drain Current	T _C = 25°C		20	А		
	TC = 100°C	I _D	12			
Pulsed Drain Current	(note1)	I _{DM}	60	А		
Gate-Source Voltage		V _{GSS}	±30	V		
Single Pulse Avalanche Energy (note2)		E _{AS}	418	mJ		
Repetitive Avalanche Energy (note2)		E _{AR}	0.63	mJ		
Avalanche Current		I _{AR}	3.4	А		
MOSFET dv/dt ruggedness, V _{DS} = 0480V		dv/dt	50	V/ns		
Power Dissipation		P _D	34	W		
Continuous Body Diode Current		I _S	20	A		
Pulsed Diode Forward Current (note1)		I _{SM}	60			
Reverse diode dv/dt (note3)		dv/dt	50	V/ns		
Maximum diode commutation speed (note3)		di _f /dt	900	A/us		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55~+150	°C		

Thermal Resistance				
Parameter	Symbol	Value	Unit	
Thermal Resistance, Junction-to-Case	R _{thJC}	3.7	°C/W	
Thermal Resistance, Junction-to-Ambient	R _{thJA}	80		



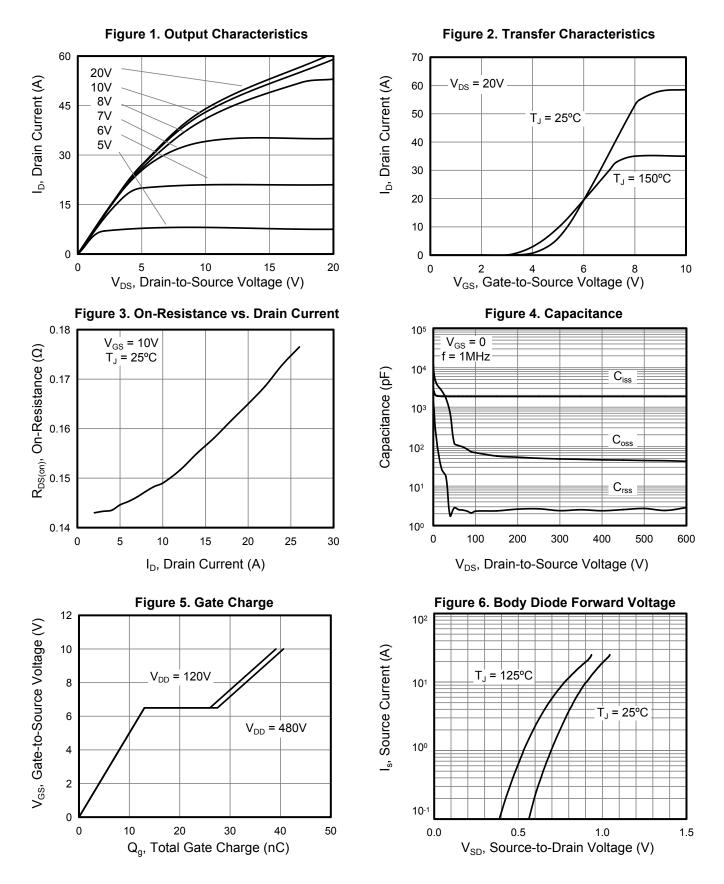
			Value			
Parameter	Symbol	Test Conditions	Min.	Typ. Max.		Unit
Static	•					
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V_{GS} = 0V, I _D = 250µA	600			V
Zero Gate Voltage Drain Current	I _{DSS}	V_{DS} = 600V, V_{GS} = 0V, T_{J} = 25°C			2.5	μA
Gate-Source Leakage	I _{GSS}	V_{GS} = $\pm 30V$			±100	nA
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	3		5	V
Drain-Source On-Resistance	R _{DS(on)}	V _{GS} = 10V, I _D = 10A		0.15	0.17	Ω
Gate resistance	R _G	f = 1.0MHz open drain		12		Ω
Dynamic						
Input Capacitance	C _{iss})/ <u>-</u> 0)/		1867		pF
Output Capacitance	C _{oss}	$V_{GS} = 0V,$ $V_{DS} = 100V,$		70		
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		2		
Total Gate Charge	Qg			41		nC
Gate-Source Charge	Q _{gs}	$V_{DD} = 480V, I_D = 20A, V_{GS} = 10V$		13		
Gate-Drain Charge	Q _{gd}			15		
Turn-on Delay Time	t _{d(on)}			39		ns
Turn-on Rise Time	t _r	V _{DD} = 400V, I _D = 20A,		39		
Turn-off Delay Time	t _{d(off)}	$R_{G} = 25\Omega$		169		
Turn-off Fall Time	t _f			49		
Drain-Source Body Diode Characte	eristics					
Body Diode Voltage	V_{SD}	T _J = 25°C, I _{SD} = 10A, V _{GS} = 0V		1.0	1.5	V
Reverse Recovery Time	t _{rr}			144		ns
Reverse Recovery Charge	Q _{rr}	V _R = 400V, I _F = I _S , di _r /dt = 100A/µs		0.76		μC
Peak Reverse Recovery Current	I _{rrm}	all at 100, pho		10.5		А

Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. I_{AS} = 3.4A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C
- 3. Identical low side and high side switch with identical ${\sf R}_{\sf G}$

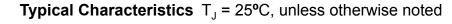


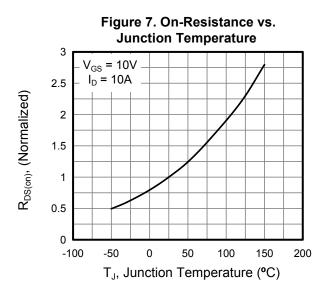
Typical Characteristics $T_J = 25^{\circ}C$, unless otherwise noted

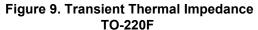


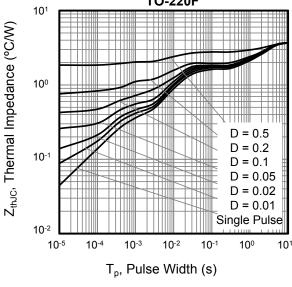
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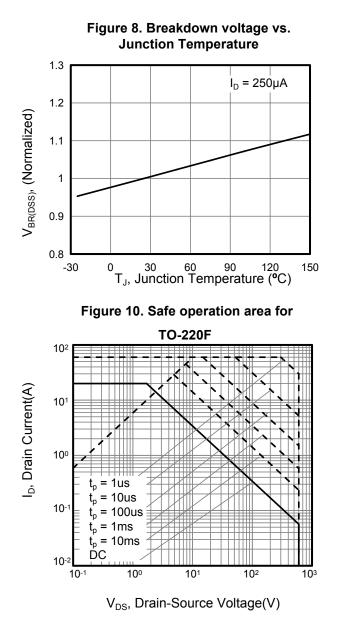
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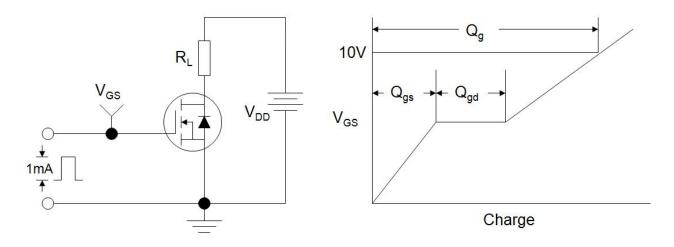


Figure B: Resistive Switching Test Circuit and Waveform

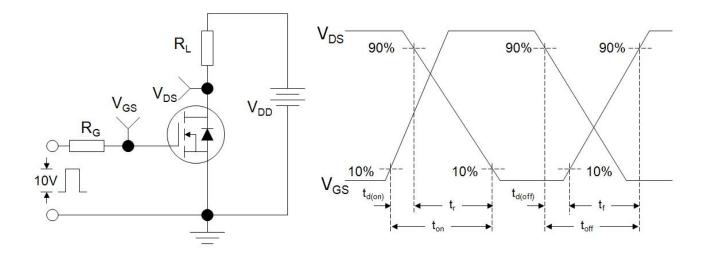
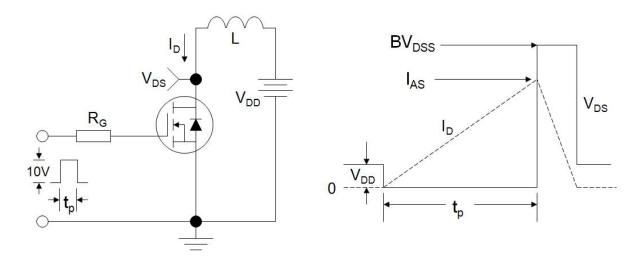
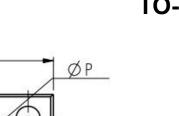


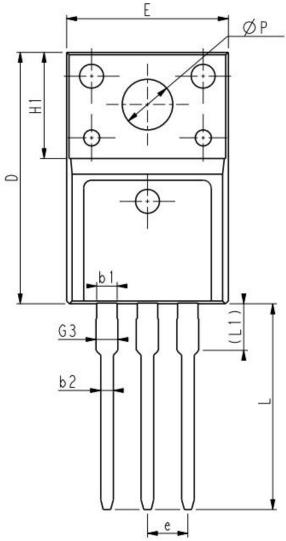
Figure C: Unclamped Inductive Switching Test Circuit and Waveform

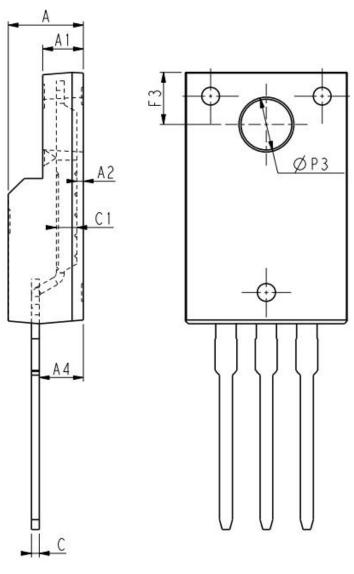






TO-220F





Max.

13.28

3.13

3.38

3.65

3.45

1.55

1.43

0.95

	Unit:mm			Unit:mm		
Symbol	Min.	Nom	Max.	Symbol	Min.	Nom
E	9.96	10.16	10.36	е		2.54BSC
А	4.50	4.70	4.90	L	12.68	12.98
A1	2.34	2.54	2.74	L1	2.93	3.03
A2	0.30	0.45	0.60	ΦΡ	3.03	3.18
A4	2.56	2.76	2.96	ΦΡ3	3.15	3.45
С	0.40	0.50	0.65	F3	3.15	3.30
c1	1.20	1.30	1.35	G3	1.25	1.35
D	15.57	15.87	16.17	b1	1.18	1.28
H1		6.70REF		b2	0.70	0.80



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